

## TRIPLE 3 INPUT OR GATE

- HIGH SPEED  
 $t_{PD} = 8 \text{ ns (TYP.) AT } V_{CC} = 5 \text{ V}$
- LOW POWER DISSIPATION  
 $I_{CC} = 1 \mu\text{A (MAX.) AT } T_A = 25^\circ\text{C}$
- HIGH NOISE IMMUNITY  
 $V_{NIH} = V_{NIL} = 28 \% V_{CC} (\text{MIN.})$
- OUTPUT DRIVE CAPABILITY  
10 LSTTL LOADS
- SYMMETRICAL OUTPUT IMPEDANCE  
 $|I_{OH}| = I_{OL} = 4 \text{ mA (MIN.)}$
- BALANCED PROPAGATION DELAYS  
 $t_{PLH} = t_{PHL}$
- WIDE OPERATING VOLTAGE RANGE  
 $V_{CC} (\text{OPR}) = 2 \text{ V TO } 6 \text{ V}$
- PIN AND FUNCTION COMPATIBLE WITH  
4075B

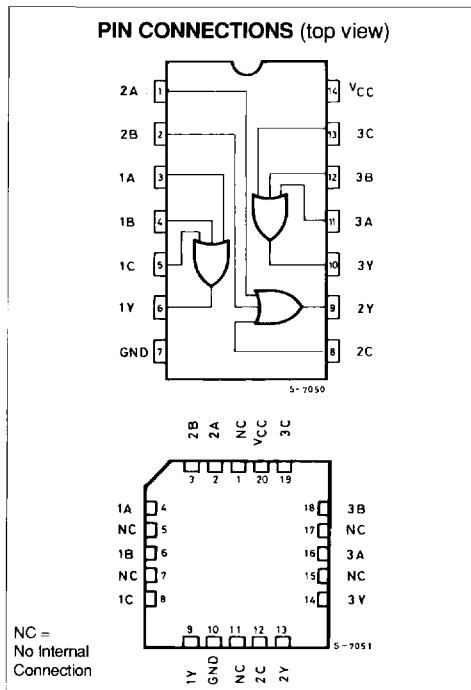
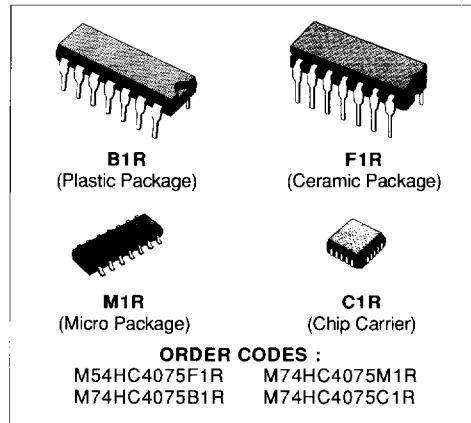
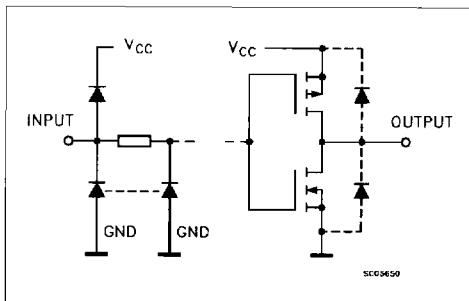
### DESCRIPTION

The M54/74HC4075 is a high speed CMOS TRIPLE 3-INPUT OR GATE fabricated in silicon gate  $C^2MOS$  technology. It has the same high speed performance of LSTTL combined with true CMOS low power consumption.

The internal circuit is composed of 4 stages including buffered output, which gives high noise immunity and a stable output.

All inputs are equipped with protection circuits against static discharge and transient excess voltage.

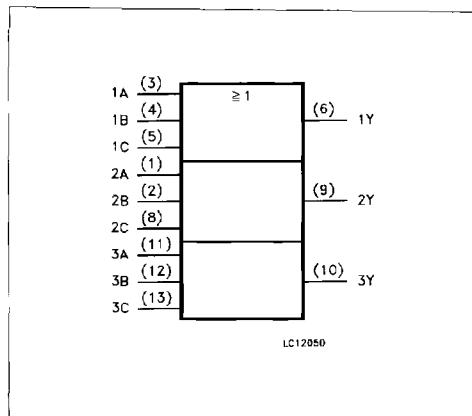
### INPUT AND OUTPUT EQUIVALENT CIRCUIT



## TRUTH TABLE

A	B	C	Y
L	L	L	L
H	X	X	H
X	H	X	H
X	X	H	H

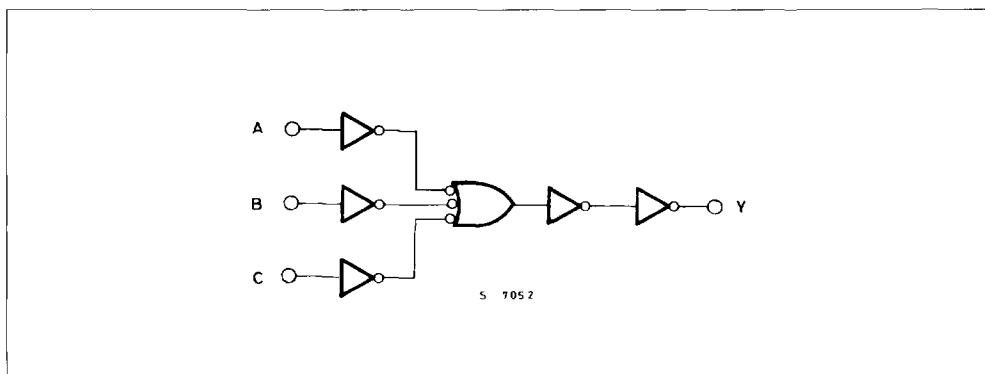
## IEC LOGIC SYMBOL



## PIN DESCRIPTION

PIN No	SYMBOL	NAME AND FUNCTION
3, 1, 11	1A to 3A	Data Inputs
4, 2, 12	1B to 3B	Data Inputs
5, 8, 13	1C to 3C	Data Inputs
6, 9, 10	1Y to 3Y	Data Outputs
7	GND	Ground (0V)
14	V <sub>CC</sub>	Positive Supply Voltage

## SCHEMATIC CIRCUIT (Per Gate)



## ABSOLUTE MAXIMUM RATINGS

Symbol	Parameter	Value	Unit
V <sub>CC</sub>	Supply Voltage	-0.5 to +7	V
V <sub>I</sub>	DC Input Voltage	-0.5 to V <sub>CC</sub> + 0.5	V
V <sub>O</sub>	DC Output Voltage	-0.5 to V <sub>CC</sub> + 0.5	V
I <sub>IK</sub>	DC Input Diode Current	± 20	mA
I <sub>OK</sub>	DC Output Diode Current	± 20	mA
I <sub>O</sub>	DC Output Source Sink Current Per Output Pin	± 25	mA
I <sub>CC</sub> or I <sub>GND</sub>	DC V <sub>CC</sub> or Ground Current	± 50	mA
P <sub>D</sub>	Power Dissipation	500 (*)	mW
T <sub>STG</sub>	Storage Temperature	-65 to +150	°C
T <sub>L</sub>	Lead Temperature (10 sec)	300	°C

Absolute Maximum Ratings are those values beyond which damage to the device may occur. Functional operation under these condition is not implied.

(\*) 500 mW:  $\equiv$  65 °C derate to 300 mW by 10mW/°C: 65 °C to 85 °C

## RECOMMENDED OPERATING CONDITIONS

Symbol	Parameter	Value		Unit	
V <sub>CC</sub>	Supply Voltage	2 to 6		V	
V <sub>I</sub>	Input Voltage	0 to V <sub>CC</sub>		V	
V <sub>O</sub>	Output Voltage	0 to V <sub>CC</sub>		V	
T <sub>op</sub>	Operating Temperature: M54HC Series M74HC Series	-55 to +125 -40 to +85		°C °C	
t <sub>r</sub> , t <sub>f</sub>	Input Rise and Fall Time	V <sub>CC</sub> = 2 V	0 to 1000		
		V <sub>CC</sub> = 4.5 V	0 to 500		
		V <sub>CC</sub> = 6 V	0 to 400		

## DC SPECIFICATIONS

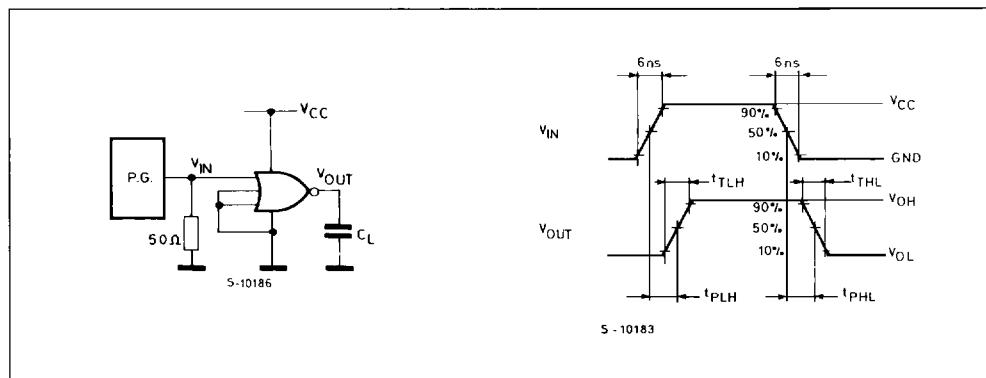
Symbol	Parameter	Test Conditions		Value						Unit	
		V <sub>CC</sub> (V)		T <sub>A</sub> = 25 °C 54HC and 74HC			-40 to 85 °C 74HC		-55 to 125 °C 54HC		
				Min.	Typ.	Max.	Min.	Max.	Min.	Max.	
V <sub>IH</sub>	High Level Input Voltage	2.0		1.5			1.5		1.5		V
		4.5		3.15			3.15		3.15		
		6.0		4.2			4.2		4.2		
V <sub>IL</sub>	Low Level Input Voltage	2.0				0.5		0.5		0.5	V
		4.5				1.35		1.35		1.35	
		6.0				1.8		1.8		1.8	
V <sub>OH</sub>	High Level Output Voltage	2.0	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>	1.9	2.0		1.9		1.9		V
		4.5		4.4	4.5		4.4		4.4		
		6.0		5.9	6.0		5.9		5.9		
		4.5	I <sub>O</sub> = 4.0 mA	4.18	4.31		4.13		4.10		
		6.0		5.68	5.8		5.63		5.60		
V <sub>OL</sub>	Low Level Output Voltage	2.0	V <sub>I</sub> = V <sub>IH</sub> or V <sub>IL</sub>		0.0	0.1		0.1		0.1	V
		4.5			0.0	0.1		0.1		0.1	
		6.0			0.0	0.1		0.1		0.1	
		4.5	I <sub>O</sub> = 4.0 mA		0.17	0.26		0.33		0.40	
		6.0			0.18	0.26		0.33		0.40	
I <sub>I</sub>	Input Leakage Current	6.0	V <sub>I</sub> = V <sub>CC</sub> or GND			±0.1		±1		±1	µA
I <sub>CC</sub>	Quiescent Supply Current	6.0	V <sub>I</sub> = V <sub>CC</sub> or GND			1		10		20	µA

AC ELECTRICAL CHARACTERISTICS ( $C_L = 50 \text{ pF}$ , Input  $t_r = t_f = 6 \text{ ns}$ )

Symbol	Parameter	Test Conditions			Value				Unit	
		$V_{CC}$ (V)	$T_A = 25^\circ\text{C}$ 54HC and 74HC			$-40 \text{ to } 85^\circ\text{C}$ 74HC		$-55 \text{ to } 125^\circ\text{C}$ 54HC		
			Min.	Typ.	Max.	Min.	Max.	Min.		
$t_{TLH}$ $t_{THL}$	Output Transition Time	2.0		30	75		95		ns	
		4.5		8	15		19			
		6.0		7	13		16			
$t_{PLH}$ $t_{PHL}$	Propagation Delay Time	2.0		40	80		100		ns	
		4.5		10	16		20			
		6.0		9	14		17			
$C_{IN}$	Input Capacitance			5	10		10		pF	
$C_{PD} (*)$	Power Dissipation Capacitance			24					pF	

(\*)  $C_{PD}$  is defined as the value of the IC's internal equivalent capacitance which is calculated from the operating current consumption without load.  
(Refer to Test Circuit). Average operating current can be obtained by the following equation.  $I_{CC(\text{opr})} = C_{PD} \cdot V_{CC} \cdot f_{IN} + I_{CC(\text{GATE})}$  (per Gate)

## SWITCHING CHARACTERISTICS TEST CIRCUIT

TEST CIRCUIT  $I_{CC}$  (Opr.)